



## **Reliability Engineering: Will my design work over the long term?**

**CMPE349 Intro to Professional Practic**

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### **The “ilities”**

- **Reliability**
- **Availability**
- **Integrity**
- **Supportability**
- **Maintainability**
- **Portability**
  
- **Tend to be driven by the hardware/software architecture and *not* functional considerations**
- **Definitions are the key! YOU are responsible!**
- **Should be considered at block diagram level**
- **An analysis task that no one teaches or talks about**

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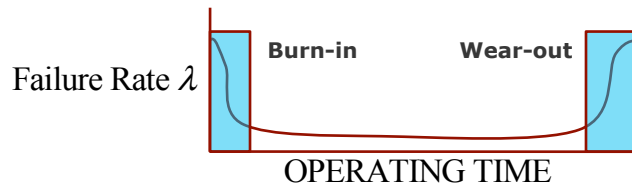
## Strawman “ility” definitions

- **Reliability**
  - Probability that the system remains operational over some time interval
  - **Generally a** long term average over a large population
  - Statistic: Mean time between failure
- **Availability**
  - Probability that the system will be operating within its performance specifications when needed by the user
  - Generally a long term average over a large population
  - Statistic: Mean time between outage
- **Continuity**
  - Probability that the system will *remain in service* over a specified (short) interval, given that it was in service at the start of that interval
  - Sometimes equivalent to Probability of Mission Success
  - **Not** just short-term availability!

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## The foundations

- Physical devices are characterized by a number called the *failure rate*,  $\lambda$ , usually given in “failures per million hours”
- The failure rate is assumed constant over time...
- ...except at the very beginning of operation
- ...and at the very end of lifetime
- Failures are assumed to be independent of each other...
- ...but this is actually a *design constraint*



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## Independence

- Two events  $X$  and  $Y$  are called *independent* if

$$\Pr\{X \text{ and } Y\} = \Pr\{X\} \times \Pr\{Y\}$$

- If  $X$  and  $Y$  are independent, their *complements* are as well

$$\begin{aligned} \Pr\{\text{NOT}(X) \text{ and } \text{NOT}(Y)\} &= \Pr\{\text{NOT}(X \text{ or } Y)\} \\ &= 1 - (\Pr\{X \text{ or } Y\}) \\ &= 1 - (\Pr\{X\} + \Pr\{Y\} - \Pr\{X \text{ AND } Y\}) \\ &= 1 - \Pr\{X\} - \Pr\{Y\} + \Pr\{X\} \Pr\{Y\} \\ &= (1 - \Pr\{X\}) \times (1 - \Pr\{Y\}) \\ &= \Pr\{\text{NOT}(X)\} \times \Pr\{\text{NOT}(Y)\} \end{aligned}$$

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## Some additional clarifications

- The *reliability* is the probability that the system is operational over some period.
- The *unreliability* is the probability that the system has failed over some period.
- Both the reliability and the unreliability are functions of time, and are frequently written as  $R(t)$ , and  $U(t)$ , respectively.
- Reliability* and *Unreliability* are complements of each other, because the element is either operating or not operating. Therefore,  $U(t) = 1 - R(t)$
- The general assumption is that the time before a failure is an exponentially distributed random variable

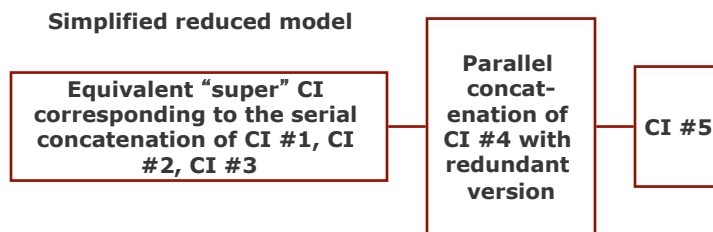
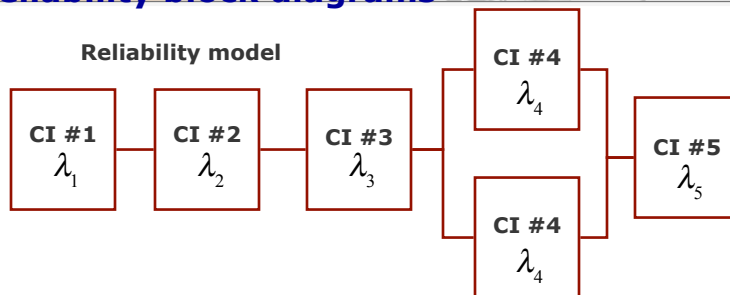
$$\begin{aligned} p_T(t) &= \lambda e^{-\lambda t}, \quad 0 \leq t \quad E(t) = \int_0^{\infty} \lambda \tau e^{-\lambda \tau} d\tau = \frac{1}{\lambda} \triangleq MTBF \\ \Pr\{t < T\} &= \int_0^T p_T(t) dt = 1 - e^{-\lambda T} = U(T) = \Pr\{\text{at least one failure in } T\} \\ \Pr\{t \geq T\} &= \int_T^{\infty} p_T(t) dt = e^{-\lambda T} = R(T) = \Pr\{\text{no failures in time } T\} \end{aligned}$$

## And still more

- For serial elements, *all* must be operating in order for the system to be operating. The reliability is, therefore, the *product* of the individual reliabilities.
- For parallel elements with only a single element required, *all* must be failed before the combination fails. The unreliability is, therefore the product of the unreliabilities, and the reliability  $R(t) = 1 - U(t)$
- The “M-of-N” combinations are harder to analyze...
- ...but you can find your way using the binomial distribution

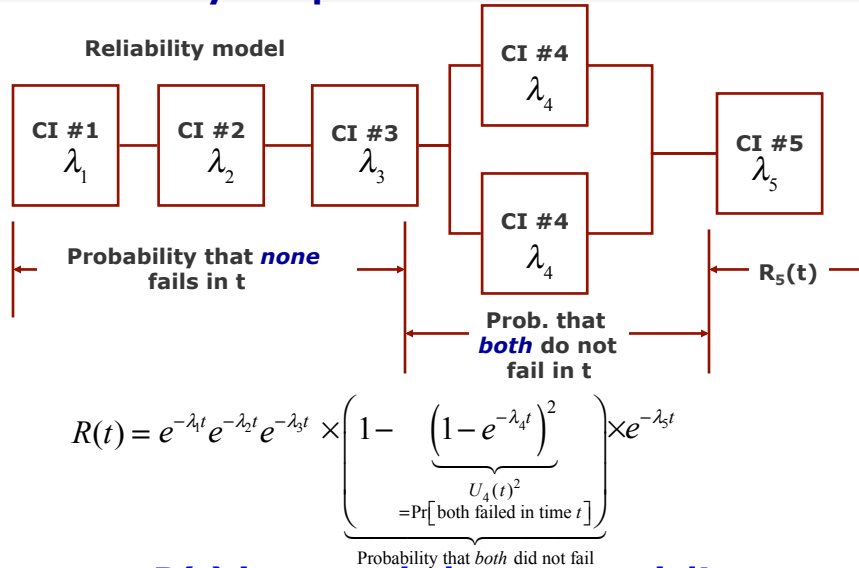
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## Reliability block diagrams



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## Reliability computations



▪  **$R(t)$  is not strictly exponential!**

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## Let's do an (extended) example

- Consider the airborne part of your landing system
- $\lambda$  is given in failure rate per hour or per million hours
- The system spec is to have a system availability of at least

$1 - 2 \times 10^{-4}$  per 2 hour mission



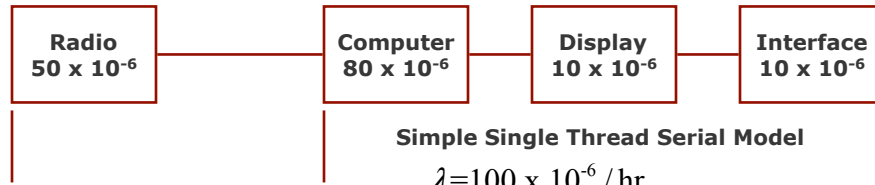
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## First: How does the simple system perform?

$$\lambda = 150 \times 10^{-6} / \text{hr} = 1.5 \times 10^{-4} / \text{hr}$$

$$R(t) = e^{-\lambda t} \approx 1 - \lambda t = 1 - (1.5 \times 10^{-4} / \text{hr} \times 2 \text{ hr}) \approx 1 - 3 \times 10^{-4} = 0.9997$$

$$U(t) = 1 - R(t) \approx 3 \times 10^{-4} > 2 \times 10^{-4}$$



Simple Single Thread Serial Model

$$\lambda = 50 \times 10^{-6} / \text{hr}$$

$$R(t) \approx 1 - \lambda t = 1 - 1 \times 10^{-4}$$

$$U(t) = 1 - R(t) \approx 1 \times 10^{-4}$$

$$\lambda = 100 \times 10^{-6} / \text{hr}$$

$$R(t) \approx 1 - \lambda t = 1 - 2 \times 10^{-4}$$

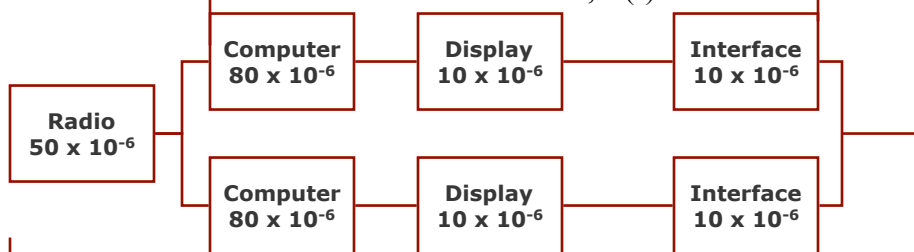
$$U(t) = 1 - R(t) \approx 2 \times 10^{-4}$$

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## Exercise results

Simple Single Thread Serial Model

$$\lambda = 100 \times 10^{-6} = 1 \times 10^{-4} / \text{hr}, R(t) = 1 - 2 \times 10^{-4}$$



Dual Thread Serial Model

$$R_{DUAL}(t) = 1 - U^2(t) = 1 - (2 \times 10^{-4})^2 = 1 - 4 \times 10^{-8}$$

$$R_{TOTAL}(t) = R_{RADIO}(t) \times R_{DUAL}(t)$$

$$= (1 - 1 \times 10^{-4}) \times (1 - 4 \times 10^{-8}) = 1 - 1.0004 \times 10^{-4} + 4 \times 10^{-12}$$

$$\approx 1 - 1 \times 10^{-4} > 1 - 2 \times 10^{-4}$$

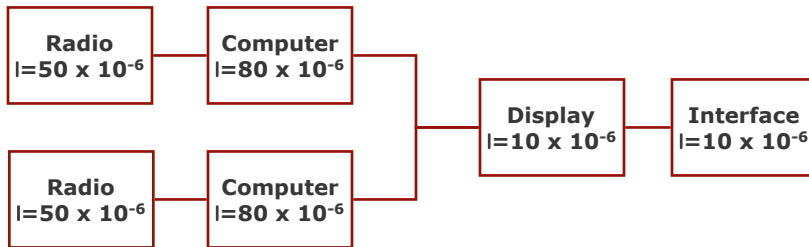
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## Design for greater availability margin!

$$\lambda = 50 \times 10^{-6} + 80 \times 10^{-6} = 1.3 \times 10^{-4}$$

$$R_{SINGLE}(t) = 1 - 2.6 \times 10^{-4}$$

$$U_{SINGLE}(t) = 2.6 \times 10^{-4}$$



$$\lambda = 10 \times 10^{-6} + 10 \times 10^{-6} = 2 \times 10^{-5}$$

$$R_{ID}(t) = 1 - 4 \times 10^{-5}$$

$$U_{ID}(t) = 4 \times 10^{-5}$$

$$R_{DUAL}(t) = 1 - (2.6 \times 10^{-4})^2 \approx 1 - 7 \times 10^{-8} \quad (!)$$

$$U_{DUAL}(t) \approx 7 \times 10^{-8}$$

$$\begin{aligned}
 R_{TOTAL}(2 \text{ hrs}) &= R_{DUAL} \times R_{ID} \\
 &= (1 - 7 \times 10^{-8}) \times (1 - 4 \times 10^{-5}) \\
 &= 1 - 4.007 \times 10^{-5} + 2.8 \times 10^{-12} \\
 &= 1 - 4 \times 10^{-5} > 1 - 2 \times 10^{-4}
 \end{aligned}$$

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## A few words about software reliability (C. LaBerge's view)

- The exponential failure rate assumption characterizes the aging of the hardware components as a function of time.
- The exponential failure rate assumption implicitly includes fault-free design!
  - The design faults are so rare that they are masked by component aging failures
- Software components never wear out: **the exponential failure assumption does not hold!**
- Because there is no masking effect, software faults are always design failures.
- The only recognized technique to eliminate design failures is design process
- Modern research continues in formal techniques to prove correctness, but this just pushes the **difficulties to a lower level.**

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## A few more words about software reliability (R. Taylor's view)



- Software “reliability” **can** be modeled as exponential, especially when operating systems are involved
- When software runs for an extended period of time, the complex and non-deterministic interaction between the operating system and the executing software result in a succession of completely unique states that can not have been tested...
- ...and this weakens (eliminates) the independence assumption.
- The time-dependent accumulation of minor flaws in the operating system – e.g., memory leaks – tend to accumulate in a random fashion and eventually cause a very low level fault of some kind.
- This fault occurs at a rate that may be somewhat less than exponential, but somewhat more than linear with time.

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## Continuity (of service)



- **Conditional Probability**
  - It worked when I started the mission, what's the probability that it works throughout the mission?
  - Example: Automatic precision landing
- This is *not* just a short term availability
- Example: Consider two systems with 90% availability over 1000 hours
  - System 1: up for 900 continuous hours, down for 100
  - System 2: up for 0.9 continuous hours, down for 0.1
- Which has better continuity for a 2 hour mission?

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## Example

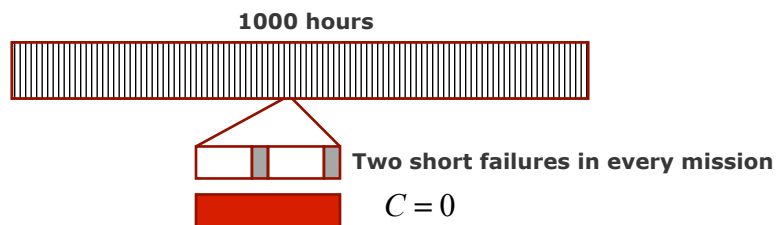
900 hrs	100 hrs
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900 hrs where Pr(completed mission)=1	98 hrs
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2 hrs where Pr(completed mission)=0

$$C = \frac{900 \times 1 + 2 \times 0}{902} = 0.997783 = \frac{450}{451}$$



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## End of Day 1

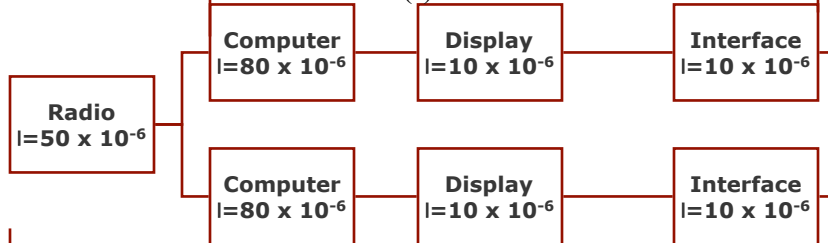
- **Reliability**
  - Probability that the system works over a period of time
  - Usually assume exponentially distributed failure times
  - The failure rate is assumed constant over the lifetime
- **Redundancy**
  - Redundancy can improve Availability, but may actually hurt reliability...
  - ...because there are more parts to fail.
- **Continuity**
  - Probability that the system works over my mission time, given that it was working before I started.
  - Frequently confused with short term availability...
  - ...but this can be misleading
- **Next time: we'll talk more carefully about availability**

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## Exercise results

### Simple Single Thread Serial Model

$$R(t) = 1 - 2 \times 10^{-4}$$



### Dual Thread Serial Model

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$$\begin{aligned}
 R_{TOTAL}(t) &= R_{RADIO}(t) \times R_{DUAL}(t) \\
 &= (1 - 1 \times 10^{-4}) \times (1 - 4 \times 10^{-8}) = 1 - 1.0004 \times 10^{-4} + 4 \times 10^{-12} \\
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